

# < GaN MMIC Power Amplifier for satellite communication (SATCOM) earth station > **MGFG5H1503**

Ku band GaN MMIC Power Amplifier

13.75 - 14.5 GHz BAND / 20W

### DESCRIPTION

The MGFG5H1503, a 20W 4-stage GaN MMIC Power Amplifier including a linearizer, is designed for Ku-band applications.

### **FEATURES**

- High voltage operation
- High output power
- : Po=43.0dBm (TYP.) @Pin=27dBm High efficiency : PAE=20% (TYP.) @Pin=27dBm

: VDS=24V

- Input and output matched to 500hm
- DC block capacitors built in
- 0.25um GaN HEMT Technology
- Independently adjustable bias pins
- Compact metal package with screw holes

### **APPLICATION**

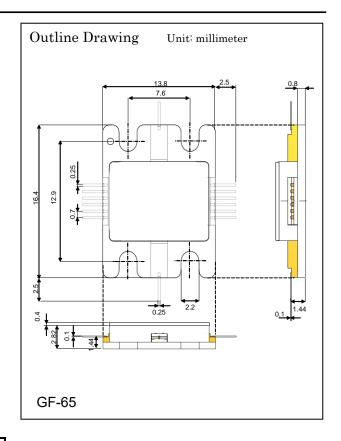
Amplifier for Ku-band SATCOM

### QUALITY

General & Industrial

### Packaging

• Tray : 12 devices in one tray



### Absolute Maximum Ratings (Ta=25°C)

Symbol	Parameter	Ratings	Unit
Vd	Drain to Source Voltage	27	V
Vg	Gate to Source Voltage	-10	V
VI	Linearizer Voltage	10	V
Pin	RF Input Power	30	dBm
Vd_on	Drain to Source Voltage under RF operation	27	V
Tch	Channel Temperature 2		°C
Tstg	Storage Temperature	-55 to 125	°C

\*1:Tc=25°C

### **Recommended Operating Conditions**

Symbol	Parameter	Тур.	Unit
Vd	Drain Voltage	24	V
IdqB	Drain Current of buffer amp. without RF Drive	180	mA
ldq1	Drain Current of 1st stage without RF Drive	360	mA
ldq2	Drain Current of 2ndstage without RF Drive	720	mA
ldq3	Drain Current of 3rd stage without RF Drive	1440	mA
Vg	Gate Voltage	-2.7 to -1.7	V
VI	Control Voltage of Linearizer	0	V
Tch	Channel Temperature	≦175	°C

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### Electrical Characteristics (Ta=25°C)

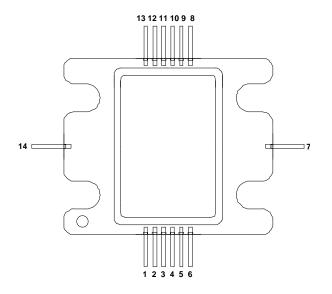
Symbol	Parameter	Test conditions Limits			Unit	
			Min.	Тур.	Max.	
Vg(off)	Gate to source cut-off voltage	Vd=24V, IdB=1.2mA	-2	-	-5	V
		Id1=2.4mA, Id2=4.8mA, Id3=9.6mA				
Freq.	Operational Frequency	Vd=24V, VI=0V	13.75	-	14.5	GHz
Psat *2	Saturated Power	IdqB=180mA, Idq1=360mA,	42	43	-	dBm
Glp *3	Linear Power Gain	Idq2=720mA, Idq3=1440mA,	22	24	-	dB
IM3 *4	3 <sup>rd</sup> Order Intermodulation Distortion	*2: Pin=27dBm *3,: Pin=0dBm *4: Pout=34dBm (SCL)	-25	-	-	dBc
Rth(ch-c) *5	Thermal resistance	∆Vf method	-	1.2	1.5	°C/W

\*5 :Channel-case

Specifications are subject to change without notice.

ESD *6	Class 0	-199~	
*6 :Based on EIAJ ED-4701 C-111A(C=100pF,R=1.5k Ω )			

### **Pin Configuration**



Pin Number	Symbol	Description
1	VdB	Drain Voltage of Buffer Stage
2	Vd1	Drain Voltage of 1st Stage
3	Vg2	Gate Voltage of 2nd Stage
4	Vd2	Drain Voltage of 2nd Stage
5	Vg3	Gate Voltage of 3rd Stage
6	Vd3	Drain Voltage of 3rd Stage
7	Pout	RF Output
8	Vd3	Drain Voltage of 3rd Stage
9	Vg3	Gate Voltage of 3rd Stage
10	Vd2	Drain Voltage of 2nd Stage
11	Vd1	Drain Voltage of 1st Stage
12	VgB1	Gate Voltage of 1st Stage and Buffer Stage
13	VI	Control Voltage of Linearizer
14	Pin	RF Input

VI: Control voltage to optimize distortion characteristics such as AMAM, AMPM, and IMD.

Vg3 and Vd1,2,3 must be biased from both sides as follows:

Vd1: <u>2 and 11</u> Vd2: <u>4 and 10</u> Vg3: <u>5 and 9</u> Vd3: <u>6 and 8</u>

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## MGFG5H1503 stand-alone

## 1. Po / GLP / PAE vs. freq

## (Temperature Dependence)

Vd=24V, VI=0V, IdqB=180mA, Idq1=360mA, Idq2=720mA, Idq3=1440mA, Tc=-15 $^{\circ}C/+25^{\circ}C/+85^{\circ}C$ 

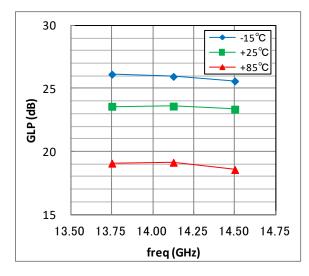


Fig.1-1 Psat@Pin=27dBm vs. Freq.

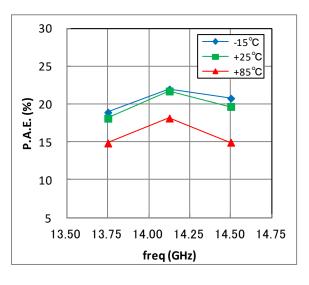


Fig.1-3 PAE@Pin=27dBm vs. Freq.

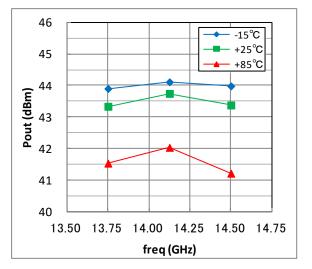


Fig.1-2 GLP@Pin=0dBm vs. Freq.

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## 2. Pin - Po Characteristics

## (Temperature Dependence)

Vd=24V, VI=0V, IdqB=180mA, Idq1=360mA, Idq2=720mA, Idq3=1440mA, Tc=-15°C/+25°C/+85°C

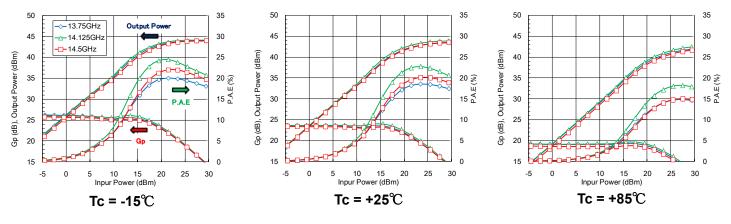


Fig.2 Pin - Po Characteristics

# 3. TWO-TONE Characteristics

## (Temperature Dependence)

Vd=24V, VI=0V, IdqB=180mA, Idq1=360mA, Idq2=720mA, Idq3=1440mA,  $\Delta$ f=5MHz in 2-tone test, Tc=-15°C/+25°C/+85°C

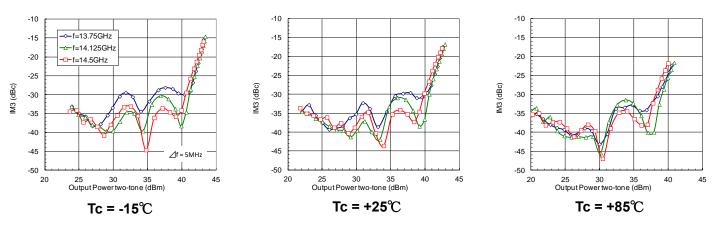


Fig.3 IM3 - Po Characteristics

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